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TOF-SIMS molecular depth profiling of polymers and organic materials using low energy atomic primary ions for sputtering

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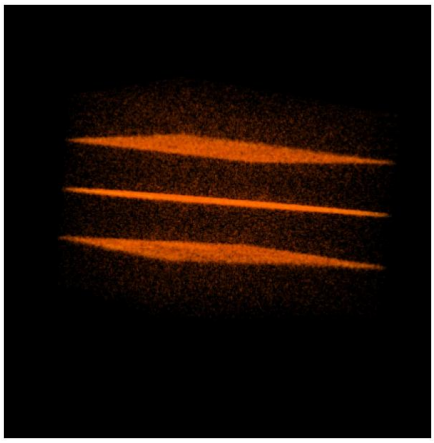
ToF-SIMS molecular depth profiling of polymers and organic materials using low energy atomic primary ions for sputtering

(Profilage moléculaire de polymères et de matériaux organiques en ToF-SIMS à l'aide d'ions primaires atomiques de basse énergie pour l'érosion.)



Thèse présentée par
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du grade de Docteur en Sciences

Faculté des Sciences

Département de Physique
Centre de Recherche en Physique
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